

The Modified Ferrell and Chhoker's Model for the Optimal Inspection Policy

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Abstract

A mathematical model developed by Ferrell and Chhoker can be used to design both 100% inspection and single sampling plans when the inspection error exists. However, they have neglected the effect of 0% inspection cost in the model. In this study, the modified model is proposed for selecting the optimal inspection policy.

Keywords: Modified Ferrell and Chhoker's Model, Sampling Plans, Optimal Inspection Policy.